Searcn Notes				

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/091,769	SUNG WON LEE	
Examiner	Art Unit	
Binh Q. Nguyen	2664	

SEARCHED			
Class	Subclass	Date	Examiner
370	336	11/17/2005	BQN
370	342	11/17/2005	BQN
370	465	11/17/2005	BQN
370	392	11/17/2005	BQN
455	466	11/17/2005	BQN
370	331	11/17/2005	BQN
370	389	11/17/2005	BQN

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	l			

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
EAST (US-GPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM-TDB), see more on search history.	11/17/2005	BQN
Consulted with SPE Wellington Chin	11/17/2005	BQN
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